


<b>Search Notes</b>  	<b>Application/Control No.</b>  10671271	<b>Applicant(s)/Patent Under Reexamination</b>  SUN ET AL.
	<b>Examiner</b>  Hung, Yubin	<b>Art Unit</b>  2624

SEARCHED			
Class	Subclass	Date	Examiner
382	103,107,117,118,164,165,194,203,260,265	3/2/07	YH
348	155,606,610,625	3/2/07	YH
358	532	3/2/07	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	3/2/07	YH
ACM	3/1/07	YH
SPIE	3/2/07	YH
IEEE Xplore	3/2/07	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner